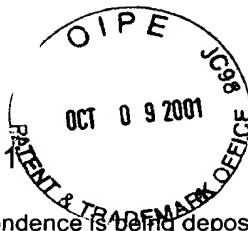


Docket No.: 2000P15141



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By: *R. P.*

Date: October 5, 2001

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Frank Pietzschmann
Applic. No. : 09/923,720
Filed : August 6, 2001
Title : Test Apparatus for Semiconductor Circuit and Method of Testing Semiconductor Circuits

INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner of Patents and Trademarks,
Washington, D.C. 20231

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

United States Patent No. 5,804,983 (Nakajima et al.), dated September 8, 1998;

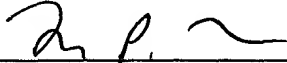
German Published, Non-Prosecuted Patent Application DE 196 48 475 A1 (Watanabe et al.), dated June 5, 1997, micro contact pin structure, testing card using it and production method;

German Published, Non-Prosecuted Patent Application DE 197 42 205 A1 (Heinzl et al.), dated March 12, 1998, micro positioning device.

If no translation of pertinent portions of any foreign language patents or publications mentioned above is included with the aforementioned copies of those applications,

patents and/or publications, it is because no existing translation is readily available to the applicant.

Respectfully submitted,



For Applicant

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Date: October 5, 2001

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